

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/671,786	SAKaida, HIDEYUKI	
Examiner		Art Unit		Page 1 of 1
JAYESH A. PATEL		2624		

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,226,353	05-2001	Wilkins et al.	378/98.9
*	B US-5,361,291	11-1994	Toth et al.	378/12
*	C US-5,802,137	09-1998	Wilkins, Stephen W.	378/85
*	D US-2002/0176615	11-2002	Ito, Wataru	382/132
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	0031-9007/96/2961-2964 The american Physical society. Quantitative Phase Imaging Using Hard X-Rays.
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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